

FCC TEST REPORT

APPLICANT

Hisense International Co., Ltd.

PRODUCT NAME

WCDMA Handset

MODEL NAME

HS-U688

TRADE NAME

Hisense

BRAND NAME

Hisense

FCC ID

2ADOBU688

STANDARD(S)

47 CFR Part 15 Subpart B

TEST DATE

2015-01-12 to 2015-01-23

ISSUE DATE

SHENZHEN MORLAB COMMUNICATIONS TECHNOLOGY Co., Ltd.

NOTE: This document is issued by MORLAB, the test report shall not be reproduced except in full without prior written permission of the company. The test results apply only to the particular sample(s) tested and to the specific tests carried out which is available on request for

validation and information confirmed at our website.

MORLAB GROUP

FL1-3, Building A, Feitrang Science Fairs, 190.6 Long-Griang, 190.6, Block67, BaoAn District, ShenZhen , GuangDong Province, P. R. China Http://www.morlab.cn E-mail: service@morlab.cn FL1-3, Building A, FeiYang Science Park, No.8 LongChang Road,

Tel: 86-755-36698555 Fax: 86-755-36698525



DIRECTORY

<u>1. TE</u>	CHNICAL INFORMATION5
1.1. <i>A</i>	PPLICANT INFORMATION·······5
1.2. E	QUIPMENT UNDER TEST (EUT) DESCRIPTION5
2. TE	ST RESULTS7
2.1. <i>A</i>	PPLIED REFERENCE DOCUMENTS7
3. TE	ST CONDITIONS SETTING8
	AB SELAT MORE ME AB SELAT MORE ME
3.1. 1	EST MODE8
	EST SETUP AND EQUIPMENTS LIST······9
	CONDUCTED EMISSION9
3.2.2.	RADIATED EMISSION
4. 47	CFR PART 15B REQUIREMENTS12
	E RIAL MORL MIC AR STAR MORL MIC AR I
4.1.	ONDUCTED EMISSION12
4.1.1.	REQUIREMENT
4.1.2.	TEST DESCRIPTION
4.1.3.	TEST RESULT 12
	ADIATED EMISSION·······15
	REQUIREMENT
	TEST DESCRIPTION15
	FREQUENCY RANGE OF MEASUREMENT
4.2.4.	TEST RESULT 16
ANNE	A TEST UNCERTAINTY19
ANNE	B TESTING LABORATORY INFORMATION20
ZLAB	ORLE HOR IS IN THE ORLE HORE S IN TAR OR
1. I	ENTIFICATION OF THE RESPONSIBLE TESTING LABORATORY20
2.	ENTIFICATION OF THE RESPONSIBLE TESTING LOCATION·······20



3. TEST ENVIRONMENT CONDITIONS -------20

	Change History				
Issue	Issue Date Reason for change				
1.0	2015-01-23	First edition			
"OBT	Mo.	TLAG CORLE MO IS THE CORLE			



Test Report Declaration

Applicant	Hisense International Co., Ltd.		
Applicant Address	Floor 22, Hisense Tower, 17 Donghai Xi Road, Qingdao, 266071, China		
Manufacturer	Hisense Communications Co., Ltd.		
Manufacturer Address	218,Qianwangang Road, Qingdao Economic&Technological Development Zone, Qingdao		
Product Name	WCDMA Handset		
Model Name	HS-U688		
Brand Name	Hisense		
HW Version	V2.00		
SW Version	W1001.4.01.03.US00		
Test Standards	47 CFR Part 15 Subpart B		
Test Result	PASS		

Tested by	Zhao	Xiaoyong	
A	Zhao	Xiaoyong	No.

Xīao Xiong Xiao Xiong Reviewed by

Zeng Davin Approved by



1. Technical Information

Note: Provide by applicant.

1.1. Applicant Information

Company: Hisense International Co., Ltd.

Address: Floor 22, Hisense Tower, 17 Donghai Xi Road, Qingdao, 266071, China

1.2. Equipment under Test (EUT) Description

EUT Type:	WCDMA Handset
Serial No:	(n.a., marked #1 by test site)
Hardware Version:	V2.00
Software Version:	W1001.4.01.03.US00

Power supply:	Battery				
ORLA	Brand Name:	Hisense			
	Model No.:	LP38300B			
	Serial No.:	(n.a. marked #1 by test site)			
	Capacity:	3000mAh			
	Rated Voltage:	3.8V			
	Charge Limit:	4.35V			
Ancillary Equipment:	AC Adapter (Charger for Battery)				
	Brand Name:	Hisense			
	Model No.:	A31-501000			
	Serial No.:	(n.a. marked #1 by test site)			
	Rated Input:	~ 100-240V, 50/60Hz, 200mA			
MORY ME	Rated Output:	= 5V, 1000mA			

NOTE:

- The EUT is a Mobile Phone. It supports GSM850MHz, 1900MHz, GPRS, EDGE, WCDMA Band II, Band V, HSDPA, HSUPA, HSPA+, GPS, ISM 2.4GHz Bluetooth band and WIFI (802.11b/g/n) band.
- It is equipped with a T-Flash card slot, a Micro-B USB port which can be connected to the ancillary equipments e.g. the PC.



For a more detailed description, please refer to Specification or User's Manual supplied by the applicant and/or manufacturer.





2. Test Results

2.1. Applied Reference Documents

The objective of the report is to perform testing according to 47 CFR Part 15 Subpart B:

No.	Identity	Document Title
1	47 CFR Part 15(10-1-13 Edition)	Radio Frequency Devices

Test detailed items/section required by FCC rules and results are as below:

No.	Section	Description	Result
1 8	15.107	Conducted Emission	PASS
2	15.109	Radiated Emission	PASS

NOTE: The tests were performed according to the method of measurements prescribed in ANSI C63.4-2009.



3. Test Conditions Setting

3.1. Test Mode

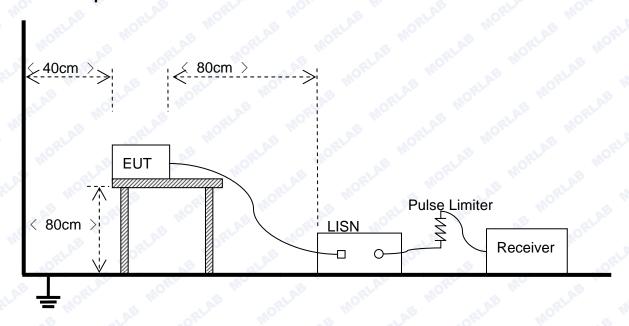
1	The first test mode (Data Transmission)					
	The EUT configuration of the emission tests is EUT + Battery + T-Flash Card + PC.					
	In this test mode, the EUT with a T-Flash Card embedded was connected to a PC via					
	the Micro-B USB port. During the measurement, the date is transmitting between the					
	PC and the T-Flash Card of the EUT.					
2	The second test mode (Standby)					
MORL	The EUT configuration of the emission tests is EUT + Battery + Charger.					
	During the measurement, the EUT was charged by its adapter and turned on.					



3.2. Test Setup and Equipments List

3.2.1. Conducted Emission

A. Test Setup:



The EUT is placed on a 0.8m high insulating table, which stands on the grounded conducting floor, and keeps 0.4m away from the grounded conducting wall. The EUT is connected to the power mains through a LISN which provides $50\Omega/50\mu H$ of coupling impedance for the measuring instrument. A Pulse Limiter is used to protect the measuring instrument. The factors of the whole test system are calibrated to correct the reading.

B. Equipments List:

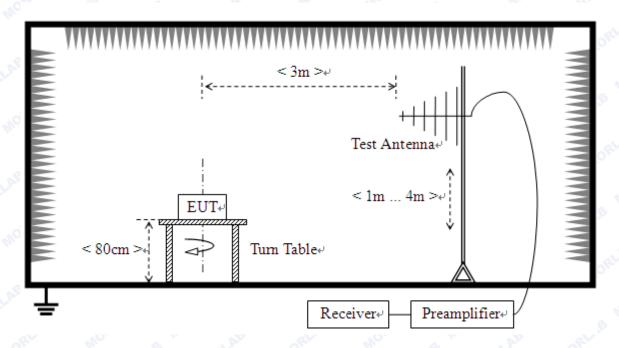
Description	Manufacturer	Model	Serial No.	Cal. Date	Due. Date
Receiver	Narda	PMM 9010	595WX11007	2014.2.21	2015.2.20
EMC Analyzer	Agilent	E7405A	US44210471	2014.2.21	2015.2.20
LISN	Schwarzbeck	NSLK 8127	812744	2014.2.24	2015.2.23
Pulse Limiter (20dB)	Schwarzbeck	VTSD 9561-D	9391	(n.a.)	(n.a.)
System Simulator	Agilent	E5515C	GB43130131	2014.2.21	2015.2.20
PC	Lenovo	ThinkPadT61	ZZF3077	(n.a.)	(n.a.)



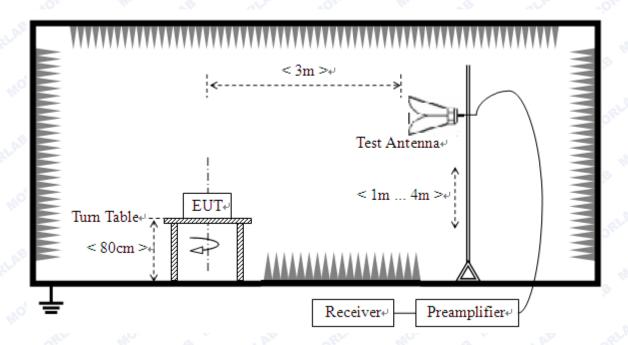
3.2.2. Radiated Emission

A. Test Setup:

For radiated emissions from 30MHz to1GHz



2. For radiated emissions above 1GHz





The test is performed in a 3m Semi-Anechoic Chamber; the antenna factor, cable loss and so on of the site (factors) is calculated to correct the reading. The EUT is placed on a 0.8m high insulating Turn Table, and keeps 3m away from the Test Antenna, which is mounted on a variable-height antenna master tower.

For the test Antenna:

In the frequency range above 30MHz, Bi-Log Test Antenna (30MHz to 1GHz) and Horn Test Antenna (above 1GHz) are used. Test Antenna is 3m away from the EUT. Test Antenna height is varied from 1m to 4m above the ground to determine the maximum value of the field strength. The emission levels at both horizontal and vertical polarizations should be tested.

B. Equipments List:

Description	Manufacturer	Model	Serial No.	Cal. Date	Due. Date
EMC Analyzer	Agilent	E7405A	US44210471	2014.2.21	2015.2.20
Receiver	Narda	PMM 9060	001WX11001	2014.2.21	2015.2.20
Receiver	Narda	PMM 9010	595WX11007	2014.2.21	2015.2.20
Semi-Anechoic Chamber	Albatross	9m*6m*6m	(n.a.)	2014.2.21	2015.2.20
Test Antenna - Bi-Log	Schwarzbeck	VULB 9163	9163-274	2014.2.25	2015.2.24
Test Antenna - Horn	Schwarzbeck	BBHA 9120D	9120D-963	2014.2.25	2015.2.24
PC PC	Lenovo	ThinkPadT61	ZZF3077	(n.a.)	(n.a.)



4. 47 CFR Part 15B Requirements

4.1. Conducted Emission

4.1.1. Requirement

According to FCC section 15.107, the radio frequency voltage that is conducted back onto the AC power line on any frequency within the band 150kHz to 30MHz shall not exceed the limits in the following table, as measured using a $50\mu\text{H}/50\Omega$ line impedance stabilization network (LISN).

Frequency range	Conducted Limit (dBµV)			
(MHz)	Quasi-peak	Average		
0.15 - 0.50	66 to 56	56 to 46		
0.50 - 5	56	46		
5 - 30	60	50		

NOTE:

- a) The limit subjects to the Class B digital device.
- b) The lower limit shall apply at the band edges.
- c) The limit decreases linearly with the logarithm of the frequency in the range 0.15 0.50MHz.

4.1.2. Test Description

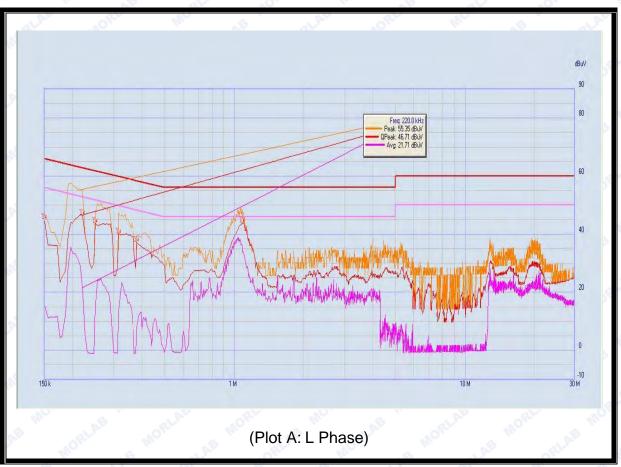
See section 3.2.1 of this report.

4.1.3. Test Result

The maximum conducted interference is searched using Peak (PK), Quasi-peak (QP) and Average (AV) detectors; the emission levels more than the AV and QP limits, and that have narrow margins from the AV and QP limits will be re-measured with AV and QP detectors. Tests for both L phase and N phase lines of the power mains connected to the EUT are performed. All test modes are considered, refer to recorded points and plots below.

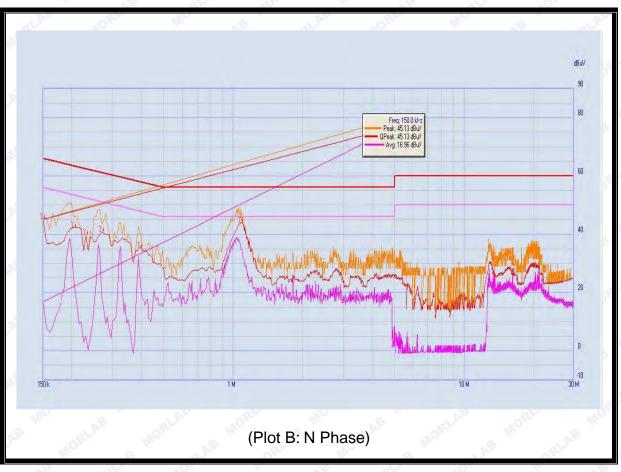
A. Test Plot and Suspicious Points:





NO.	Fre.	· · · · · · · · · · · · · · · · · · ·		Limit (d	dΒμV)	Power-line	Verdict
	(MHz)	Quai-peak	Average Quai-peak Average		Average		
1	0.15	45.07	15.85	66.00	56.00	ORLA	PASS
2	0.22	46.71	21.71	64.00	54.00	, we want	PASS
3	0.25	43.86	14.47	63.14	53.14	1:300	PASS
4	0.315	40.23	13.78	61.29	51.29	Line	PASS
5	0.38	37.34	8.09	59.43	49.43	Jen Bur	PASS
6	1.085	43.87	33.69	56.00	46.00	ORLAN	PASS





NO.	Fre.	Emission Level (dBµV)		Limit (dΒμV)	Power-line	Verdict	
(MHz)		Hz) Quai-peak Avera		Quai-peak	Quai-peak Average		13.000	
1.0	0.15	45.13	16.96	66.00	56.00	ORLA	PASS	
2	0.205	42.38	23.21	64.43	54.43	e me	PASS	
3	0.23	39.73	5.00	63.71	53.71	NauMoki	PASS	
4	0.27	40.71	18.15	62.57	52.57	Neutral	PASS	
5	0.395	35.44	23.60	59.00	49.00	Okr B W	PASS	
6	1.08	43.93	35.46	56.00	46.00	ORLAN	PASS	

Test Result: PASS



4.2. Radiated Emission

4.2.1. Requirement

According to FCC section 15.109(a), the field strength of radiated emissions from unintentional radiators at a distance of 3 meters shall not exceed the following values:

Frequency	Field St	rength		ion at 3m Measurement ist
range (MHz)	μV/m	Dist	(μV/m)	(dBµV/m)
30.0 - 88.0	100	3m	100	20log 100
88.0 - 216.0	150	3m	150	20log 150
216.0 - 960.0	200	3m	200	20log 200
Above 960.0	500	3m	500	20log 500

As shown in FCC section 15.35(b), for frequencies above 1000MHz, the field strength limits are based on average detector. When average radiated emission measurements are specified in this part, including emission measurements below 1000MHz, there also is a limit on the radio frequency emissions, as measured using instrumentation with a peak detector function, corresponding to 20dB above the maximum permitted average limit for the frequency being investigated unless a different peak emission limit is otherwise specified in the rules.

Note:

- 1) The tighter limit shall apply at the boundary between two frequency range.
- 2) Limitation expressed in dBμV/m is calculated by 20log Emission Level(μV/m).
- If measurement is made at 3m distance, then F.S Limitation at 3m distance is adjusted by using the formula of Ld1 = Ld2 * (d2/d1)².

Example:

F.S Limit at 30m distance is $30\mu\text{V/m}$, then F.S Limitation at 3m distance is adjusted as Ld1 = L1 = $30\mu\text{V/m}$ * $(10)^2$ = 100 * $30\mu\text{V/m}$

4.2.2. Test Description

See section 3.2.2 of this report.





4.2.3. Frequency range of measurement

Highest frequency generated or used in the device is the highest speed of the processor, lowest frequency generated or used in the device is the lowest frequency of the oscillator. According to 15.33(b)(1), the frequency range of radiated measurement for the EUT is listed in the following table:

Frequency	Frequency generated or used in the device	Frequency range of radiated measurement in the report
Highest	1.2GHz	6GHz

4.2.4. Test Result

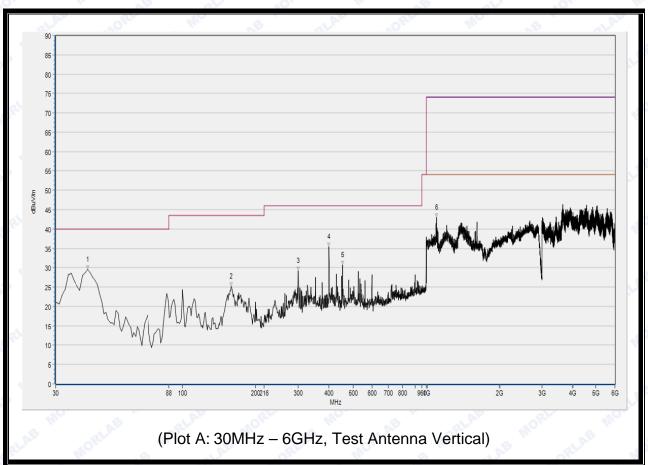
The maximum radiated emission is searched using PK, QP and AV detectors; the emission levels more than the limits, and that have narrow margins from the limits will be re-measured with AV and QP detectors. Both the vertical and the horizontal polarizations of the Test Antenna are considered to perform the tests. All test modes are considered, refer to recorded points and plots below.

The amplitude of spurious emissions which are attenuated more than 20 dB below the permissible value need not be reported.

Note: All radiated emission tests were performed in X, Y, Z axis direction, and only the worst axis test condition was recorded in this test report.

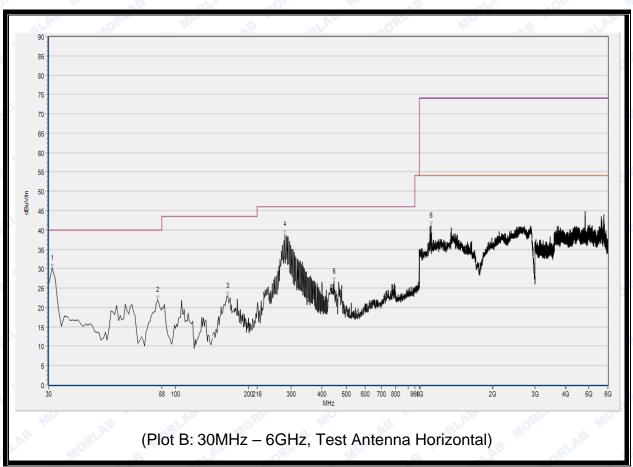
A. Test Plots and Suspicious Points:





NO.	Fre. (MHz)	Pk	QP	AV	Limit-	Limit-	Limit-	Antenna	Verdict
	LAB	ORLA	MOL	-3	PK	QP	AV	Mokey	BHILL
1	40.670	N.A	29.61	N.A	N.A	40.00	N.A	Vertical	Pass
2	159.010	N.A	25.11	N.A	N.A	43.50	N.A	Vertical	Pass
3	299.660	N.A	29.21	N.A	N.A	46.00	N.A	Vertical	Pass
4.6	399.570	N.A	35.43	N.A	N.A	46.00	N.A	Vertical	Pass
5	452.920	N.A	30.65	N.A	N.A	46.00	N.A	Vertical	Pass
6	1108.000	42.96	N.A	32.87	74.00	N.A	54.00	Vertical	Pass





Fre. (MHz)	Pk	QP	AV 🦪	Limit-	Limit-	Limit-	Antenna	Verdict
ST. MO	~	9	SLAB	PK	QP 🦠	AV	3 Miles	3
30.970	N.A	30.14	N.A	N.A	40.00	N.A	Horizontal	Pass
84.320	N.A	21.98	N.A	N.A 🦪	40.00	N.A	Horizontal	Pass
163.860	N.A	23.08	N.A	N.A	43.50	N.A	Horizontal	Pass
281.230	N.A	38.98	N.A	N.A	46.00	N.A	Horizontal	Pass
447.100	N.A	26.76	N.A	N.A	46.00	N.A	Horizontal	Pass
1121.000	41.21	N.A	32.03	74.0	N.A	54.0	Horizontal	Pass
	30.970 84.320 163.860 281.230 447.100	30.970 N.A 84.320 N.A 163.860 N.A 281.230 N.A 447.100 N.A	30.970 N.A 30.14 84.320 N.A 21.98 163.860 N.A 23.08 281.230 N.A 38.98 447.100 N.A 26.76	30.970 N.A 30.14 N.A 84.320 N.A 21.98 N.A 163.860 N.A 23.08 N.A 281.230 N.A 38.98 N.A 447.100 N.A 26.76 N.A	PK 30.970 N.A 30.14 N.A N.A 84.320 N.A 21.98 N.A N.A 163.860 N.A 23.08 N.A N.A 281.230 N.A 38.98 N.A N.A 447.100 N.A 26.76 N.A N.A	PK QP 30.970 N.A 30.14 N.A N.A 40.00 84.320 N.A 21.98 N.A N.A 40.00 163.860 N.A 23.08 N.A N.A 43.50 281.230 N.A 38.98 N.A N.A 46.00 447.100 N.A 26.76 N.A N.A 46.00	PK QP AV 30.970 N.A 30.14 N.A N.A 40.00 N.A 84.320 N.A 21.98 N.A N.A 40.00 N.A 163.860 N.A 23.08 N.A N.A 43.50 N.A 281.230 N.A 38.98 N.A N.A 46.00 N.A 447.100 N.A 26.76 N.A N.A 46.00 N.A	PK QP AV 30.970 N.A 30.14 N.A N.A 40.00 N.A Horizontal 84.320 N.A 21.98 N.A N.A 40.00 N.A Horizontal 163.860 N.A 23.08 N.A N.A 43.50 N.A Horizontal 281.230 N.A 38.98 N.A N.A 46.00 N.A Horizontal 447.100 N.A 26.76 N.A N.A 46.00 N.A Horizontal

Test Result: PASS



Annex A Test Uncertainty

The uncertainty is calculated using the methods suggested in the "Guide to the Expression of Uncertainty in Measurement" (GUM) published by ISO.

Í	Uncertainty of Conducted Emission:	±1.8dB
Ī	Uncertainty of Radiated Emission:	±3.1dB





Annex B Testing Laboratory Information

1. Identification of the Responsible Testing Laboratory

Company Name:	Shenzhen Morlab Communications Technology Co., Ltd.
Department:	Morlab Laboratory
Address:	FL.3, Building A, FeiYang Science Park, No.8 LongChang Road, Block 67, BaoAn District, ShenZhen, GuangDong Province, P. R. China
Responsible Test Lab Manager:	Mr. Su Feng
Telephone:	+86 755 36698555
Facsimile:	+86 755 36698525

2. Identification of the Responsible Testing Location

Name:	Shenzhen Morlab Communications Technology Co., Ltd.
MORL MO.	Morlab Laboratory
Address:	FL.3, Building A, FeiYang Science Park, No.8 LongChang
AL. MO. VE H.	Road, Block 67, BaoAn District, ShenZhen, GuangDong
TLAS TOPLE ME	Province, P. R. China

3. Test Environment Conditions

During the measurement, the environmental conditions were within the listed ranges:

Temperature (°C):	15 - 35
Relative Humidity (%):	30 - 60
Atmospheric Pressure (kPa):	86 - 106

***** END OF REPORT *****

